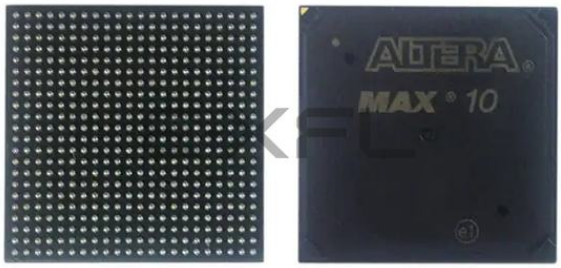

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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Active
Number of LABs/CLBs	1000
Number of Logic Elements/Cells	16000
Total RAM Bits	562176
Number of I/O	246
Number of Gates	-
Voltage - Supply	1.15V ~ 1.25V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	324-LFBGA
Supplier Device Package	324-UBGA (15x15)
Purchase URL	https://www.e-xfl.com/product-detail/intel/10m16dcu324i7g

Operating Conditions

Intel MAX 10 devices are rated according to a set of defined parameters. To maintain the highest possible performance and reliability of the Intel MAX 10 devices, you must consider the operating requirements described in this section.

Absolute Maximum Ratings

This section defines the maximum operating conditions for Intel MAX 10 devices. The values are based on experiments conducted with the devices and theoretical modeling of breakdown and damage mechanisms. The functional operation of the device is not implied for these conditions.

Caution: Conditions outside the range listed in the absolute maximum ratings tables may cause permanent damage to the device. Additionally, device operation at the absolute maximum ratings for extended periods of time may have adverse effects on the device.

Single Supply Devices Absolute Maximum Ratings

Table 2. Absolute Maximum Ratings for Intel MAX 10 Single Supply Devices

Symbol	Parameter	Min	Max	Unit
V_{CC_ONE}	Supply voltage for core and periphery through on-die voltage regulator	–0.5	3.9	V
V_{CCIO}	Supply voltage for input and output buffers	–0.5	3.9	V
V_{CCA}	Supply voltage for phase-locked loop (PLL) regulator and analog-to-digital converter (ADC) block (analog)	–0.5	3.9	V

Dual Supply Devices Absolute Maximum Ratings

Table 3. Absolute Maximum Ratings for Intel MAX 10 Dual Supply Devices

Symbol	Parameter	Min	Max	Unit
V_{CC}	Supply voltage for core and periphery	–0.5	1.63	V
V_{CCIO}	Supply voltage for input and output buffers	–0.5	3.9	V
V_{CCA}	Supply voltage for PLL regulator (analog)	–0.5	3.41	V

continued...

Table 11. ADC_VREF Pin Leakage Current for Intel MAX 10 Devices

Symbol	Parameter	Condition	Min	Max	Unit
I_{adc_vref}	ADC_VREF pin leakage current	Single supply mode	—	10	µA
		Dual supply mode	—	20	µA

Bus Hold Parameters

Bus hold retains the last valid logic state after the source driving it either enters the high impedance state or is removed. Each I/O pin has an option to enable bus hold in user mode. Bus hold is always disabled in configuration mode.

Table 12. Bus Hold Parameters for Intel MAX 10 Devices

Parameter	Condition	V_{CCIO} (V)												Unit
		1.2		1.5		1.8		2.5		3.0		3.3		
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
Bus-hold low, sustaining current	$V_{IN} > V_{IL}$ (maximum)	8	—	12	—	30	—	50	—	70	—	70	—	µA
Bus-hold high, sustaining current	$V_{IN} < V_{IH}$ (minimum)	–8	—	–12	—	–30	—	–50	—	–70	—	–70	—	µA
Bus-hold low, overdrive current	$0 V < V_{IN} < V_{CCIO}$	—	125	—	175	—	200	—	300	—	500	—	500	µA
Bus-hold high, overdrive current	$0 V < V_{IN} < V_{CCIO}$	—	–125	—	–175	—	–200	—	–300	—	–500	—	–500	µA
Bus-hold trip point	—	0.3	0.9	0.375	1.125	0.68	1.07	0.7	1.7	0.8	2	0.8	2	V

Table 19. Hysteresis Specifications for Schmitt Trigger Input for Intel MAX 10 Devices

Symbol	Parameter	Condition	Minimum	Unit
V_{HYS}	Hysteresis for Schmitt trigger input	V_{CCIO} = 3.3 V	180	mV
		V_{CCIO} = 2.5 V	150	mV
		V_{CCIO} = 1.8 V	120	mV
		V_{CCIO} = 1.5 V	110	mV

I/O Standard	$V_{IL(DC)}$ (V)		$V_{IH(DC)}$ (V)		$V_{IL(AC)}$ (V)		$V_{IH(AC)}$ (V)		V_{OL} (V)	V_{OH} (V)	I_{OL} (mA)	I_{OH} (mA)
	Min	Max	Min	Max	Min	Max	Min	Max	Max	Min		
HSTL-12 Class I	–0.15	V_{REF} – 0.08	V_{REF} + 0.08	V_{CCIO} + 0.15	–0.24	V_{REF} – 0.15	V_{REF} + 0.15	V_{CCIO} + 0.24	0.25 × V_{CCIO}	0.75 × V_{CCIO}	8	–8
HSTL-12 Class II	–0.15	V_{REF} – 0.08	V_{REF} + 0.08	V_{CCIO} + 0.15	–0.24	V_{REF} – 0.15	V_{REF} + 0.15	V_{CCIO} + 0.24	0.25 × V_{CCIO}	0.75 × V_{CCIO}	14	–14
HSUL-12	—	V_{REF} – 0.13	V_{REF} + 0.13	—	—	V_{REF} – 0.22	V_{REF} + 0.22	—	0.1 × V_{CCIO}	0.9 × V_{CCIO}	—	—

Differential SSTL I/O Standards Specifications

Differential SSTL requires a V_{REF} input.

Table 23. Differential SSTL I/O Standards Specifications for Intel MAX 10 Devices

I/O Standard	V_{CCIO} (V)			$V_{Swing(DC)}$ (V)		$V_{X(AC)}$ (V)			$V_{Swing(AC)}$ (V)	
	Min	Typ	Max	Min	Max[17]	Min	Typ	Max	Min	Max
SSTL-2 Class I, II	2.375	2.5	2.625	0.36	V_{CCIO}	$V_{CCIO}/2$ – 0.2	—	V_{CCIO}/ 2+ 0.2	0.7	V_{CCIO}
SSTL-18 Class I, II	1.7	1.8	1.9	0.25	V_{CCIO}	$V_{CCIO}/2$ – 0.175	—	V_{CCIO}/ 2+ 0.175	0.5	V_{CCIO}
SSTL-15 Class I, II	1.425	1.5	1.575	0.2	—	$V_{CCIO}/2$ – 0.15	—	$V_{CCIO}/2$ + 0.15	$2(V_{IH(AC)} – V_{REF})$	$2(V_{IL(AC)} – V_{REF})$
SSTL-135	1.283	1.35	1.45	0.18	—	V_{REF} – 0.135	0.5 × V_{CCIO}	V_{REF} + 0.135	$2(V_{IH(AC)} – V_{REF})$	$2(V_{IL(AC)} – V_{REF})$

Differential HSTL and HSUL I/O Standards Specifications

Differential HSTL requires a V_{REF} input.

(17) The maximum value for $V_{SWING(DC)}$ is not defined. However, each single-ended signal needs to be within the respective single-ended limits ($V_{IH(DC)}$ and $V_{IL(DC)}$).

Table 24. Differential HSTL and HSUL I/O Standards Specifications for Intel MAX 10 Devices

I/O Standard	V_{CCIO} (V)			$V_{DIF(DC)}$ (V)		$V_{X(AC)}$ (V)			$V_{CM(DC)}$ (V)			$V_{DIF(AC)}$ (V)
	Min	Typ	Max	Min	Max	Min	Typ	Max	Min	Typ	Max	Min
HSTL-18 Class I, II	1.71	1.8	1.89	0.2	—	0.85	—	0.95	0.85	—	0.95	0.4
HSTL-15 Class I, II	1.425	1.5	1.575	0.2	—	0.71	—	0.79	0.71	—	0.79	0.4
HSTL-12 Class I, II	1.14	1.2	1.26	0.16	V_{CCIO}	0.48 × V_{CCIO}	0.5 × V_{CCIO}	0.52 × V_{CCIO}	0.48 × V_{CCIO}	0.5 × V_{CCIO}	0.52 × V_{CCIO}	0.3
HSUL-12	1.14	1.2	1.3	0.26	—	0.5 × V_{CCIO} – 0.12	0.5 × V_{CCIO}	0.5 × V_{CCIO} + 0.12	0.4 × V_{CCIO}	0.5 × V_{CCIO}	0.6 × V_{CCIO}	0.44

Differential I/O Standards Specifications

Table 25. Differential I/O Standards Specifications for Intel MAX 10 Devices

I/O Standard	V_{CCIO} (V)			V_{ID} (mV)		V_{ICM} (V) (18)			V_{OD} (mV) (19)(20)			V_{OS} (V) (19)		
	Min	Typ	Max	Min	Max	Min	Condition	Max	Min	Typ	Max	Min	Typ	Max
LVPECL (21)	2.375	2.5	2.625	100	—	0.05	D_{MAX} ≤ 500 Mbps	1.8	—	—	—	—	—	—
						0.55	500 Mbps ≤ D_{MAX} ≤ 700 Mbps	1.8						
						1.05	D_{MAX} > 700 Mbps	1.55						
LVDS	2.375	2.5	2.625	100	—	0.05	D_{MAX} ≤ 500 Mbps	1.8	247	—	600	1.125	1.25	1.375
						0.55	500 Mbps ≤ D_{MAX} ≤ 700 Mbps	1.8						

continued...

(18) V_{IN} range: 0 V ≤ V_{IN} ≤ 1.85 V.

(19) R_L range: 90 ≤ R_L ≤ 110 Ω.

(20) Low V_{OD} setting is only supported for RSDS standard.

(21) LVPECL input standard is only supported at clock input. Output standard is not supported.

I/O Standard	V_{CCIO} (V)			V_{ID} (mV)		V_{ICM} (V) (18)			V_{OD} (mV) (19)(20)			V_{OS} (V) (19)		
	Min	Typ	Max	Min	Max	Min	Condition	Max	Min	Typ	Max	Min	Typ	Max
HiSpi	2.375	2.5	2.625	100	—	0.05	D_{MAX} ≤ 500 Mbps	1.8	—	—	—	—	—	—
						0.55	500 Mbps ≤ D_{MAX} ≤ 700 Mbps	1.8						
						1.05	D_{MAX} > 700 Mbps	1.55						

Related Information

Intel MAX 10 LVDS SERDES I/O Standards Support, Intel MAX 10 High-Speed LVDS I/O User Guide
Provides the list of I/O standards supported in single supply and dual supply devices.

Switching Characteristics

This section provides the performance characteristics of Intel MAX 10 core and periphery blocks.

(18) V_{IN} range: 0 V ≤ V_{IN} ≤ 1.85 V.
(19) R_L range: 90 ≤ R_L ≤ 110 Ω.
(20) Low V_{OD} setting is only supported for RSDS standard.

(22) No fixed V_{IN} , V_{OD} , and V_{OS} specifications for Bus LVDS (BLVDS). They are dependent on the system topology.

(23) Mini-LVDS, RSDS, and Point-to-Point Differential Signaling (PPDS) standards are only supported at the output pins for Intel MAX 10 devices.

(24) Supported with requirement of an external level shift

(25) Sub-LVDS input buffer is using 2.5 V differential buffer.

(26) Differential output depends on the values of the external termination resistors.

(27) Differential output offset voltage depends on the values of the external termination resistors.

True LVDS Transmitter Timing

Single Supply Devices True LVDS Transmitter Timing Specifications

Table 41. True LVDS Transmitter Timing Specifications for Intel MAX 10 Single Supply Devices

True **LVDS** transmitter is only supported at the bottom I/O banks.

Symbol	Parameter	Mode	–C7, –I7			–A7			–C8			Unit
			Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
f_{HSCLK}	Input clock frequency	×10	5	—	145	5	—	100	5	—	100	MHz
		×8	5	—	145	5	—	100	5	—	100	MHz
		×7	5	—	145	5	—	100	5	—	100	MHz
		×4	5	—	145	5	—	100	5	—	100	MHz
		×2	5	—	145	5	—	100	5	—	100	MHz
		×1	5	—	290	5	—	200	5	—	200	MHz
HSIODR	Data rate	×10	100	—	290	100	—	200	100	—	200	Mbps
		×8	80	—	290	80	—	200	80	—	200	Mbps
		×7	70	—	290	70	—	200	70	—	200	Mbps
		×4	40	—	290	40	—	200	40	—	200	Mbps
		×2	20	—	290	20	—	200	20	—	200	Mbps
		×1	10	—	290	10	—	200	10	—	200	Mbps
t_{DUTY}	Duty cycle on transmitter output clock	—	45	—	55	45	—	55	45	—	55	%
TCCS(63)	Transmitter channel-to-channel skew	—	—	—	300	—	—	300	—	—	300	ps
$t_{x\ Jitter}$(64)	Output jitter	—	—	—	1,000	—	—	1,000	—	—	1,000	ps

continued...

(63) TCCS specifications apply to I/O banks from the same side only.

(64) TX jitter is the jitter induced from core noise and I/O switching noise.

Dual Supply Devices Emulated LVDS_E_3R, SLVS, and Sub-LVDS Transmitter Timing Specifications

Table 44. Emulated LVDS_E_3R, SLVS, and Sub-LVDS Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices

Emulated **LVDS_E_3R**, **SLVS**, and **Sub-LVDS** transmitters are supported at the output pin of all I/O banks.

Symbol	Parameter	Mode	–I6, –A6, –C7, –I7			–A7			–C8			Unit
			Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
f_{HSCLK}	Input clock frequency (high-speed I/O performance pin)	×10	5	—	300	5	—	275	5	—	275	MHz
		×8	5	—	300	5	—	275	5	—	275	MHz
		×7	5	—	300	5	—	275	5	—	275	MHz
		×4	5	—	300	5	—	275	5	—	275	MHz
		×2	5	—	300	5	—	275	5	—	275	MHz
		×1	5	—	300	5	—	275	5	—	275	MHz
HSIODR	Data rate (high-speed I/O performance pin)	×10	100	—	600	100	—	550	100	—	550	Mbps
		×8	80	—	600	80	—	550	80	—	550	Mbps
		×7	70	—	600	70	—	550	70	—	550	Mbps
		×4	40	—	600	40	—	550	40	—	550	Mbps
		×2	20	—	600	20	—	550	20	—	550	Mbps
		×1	10	—	300	10	—	275	10	—	275	Mbps
f_{HSCLK}	Input clock frequency (low-speed I/O performance pin)	×10	5	—	150	5	—	150	5	—	150	MHz
		×8	5	—	150	5	—	150	5	—	150	MHz
		×7	5	—	150	5	—	150	5	—	150	MHz
		×4	5	—	150	5	—	150	5	—	150	MHz
		×2	5	—	150	5	—	150	5	—	150	MHz
		×1	5	—	300	5	—	300	5	—	300	MHz
HSIODR	Data rate (low-speed I/O performance pin)	×10	100	—	300	100	—	300	100	—	300	Mbps
		×8	80	—	300	80	—	300	80	—	300	Mbps

continued...

Symbol	Parameter	Mode	–I6, –A6, –C7, –I7			–A7			–C8			Unit
			Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
		×7	70	—	300	70	—	300	70	—	300	Mbps
		×4	40	—	300	40	—	300	40	—	300	Mbps
		×2	20	—	300	20	—	300	20	—	300	Mbps
		×1	10	—	300	10	—	300	10	—	300	Mbps
t_{DUTY}	Duty cycle on transmitter output clock	—	45	—	55	45	—	55	45	—	55	%
TCCS[69]	Transmitter channel-to-channel skew	—	—	—	300	—	—	300	—	—	300	ps
$t_{x\ Jitter}$[70]	Output jitter (high-speed I/O performance pin)	—	—	—	425	—	—	425	—	—	425	ps
	Output jitter (low-speed I/O performance pin)	—	—	—	470	—	—	470	—	—	470	ps
t_{RISE}	Rise time	20 – 80%, C_{LOAD} = 5 pF	—	500	—	—	500	—	—	500	—	ps
t_{FALL}	Fall time	20 – 80%, C_{LOAD} = 5 pF	—	500	—	—	500	—	—	500	—	ps
t_{LOCK}	Time required for the PLL to lock, after CONF_DONE signal goes high, indicating the completion of device configuration	—	—	—	1	—	—	1	—	—	1	ms

(69) TCCS specifications apply to I/O banks from the same side only.

(70) TX jitter is the jitter induced from core noise and I/O switching noise.

Symbol	Parameter	Mode	–C7, –I7		–A7		–C8		Unit
			Min	Max	Min	Max	Min	Max	
		×8	80	200	80	200	80	200	Mbps
		×7	70	200	70	200	70	200	Mbps
		×4	40	200	40	200	40	200	Mbps
		×2	20	200	20	200	20	200	Mbps
		×1	10	200	10	200	10	200	Mbps
SW	Sampling window (high-speed I/O performance pin)	—	—	910	—	910	—	910	ps
	Sampling window (low-speed I/O performance pin)	—	—	1,110	—	1,110	—	1,110	ps
$t_{x\ Jitter}$(71)	Input jitter	—	—	1,000	—	1,000	—	1,000	ps
t_{LOCK}	Time required for the PLL to lock, after CONF_DONE signal goes high, indicating the completion of device configuration	—	—	1	—	1	—	1	ms

Dual Supply Devices LVDS, TMDS, HiSpi, SLVS, and Sub-LVDS Receiver Timing Specifications

Table 46. LVDS, TMDS, HiSpi, SLVS, and Sub-LVDS Receiver Timing Specifications for Intel MAX 10 Dual Supply Devices

LVDS, **TMDS**, **HiSpi**, **SLVS**, and **Sub-LVDS** receivers are supported at all banks.

Symbol	Parameter	Mode	–I6, –A6, –C7, –I7		–A7		–C8		Unit
			Min	Max	Min	Max	Min	Max	
f_{HSCLK}	Input clock frequency (high-speed I/O performance pin)	×10	5	350	5	320	5	320	MHz
		×8	5	360	5	320	5	320	MHz
		×7	5	350	5	320	5	320	MHz
		×4	5	360	5	320	5	320	MHz

continued...

(71) TX jitter is the jitter induced from core noise and I/O switching noise.

Symbol	Parameter	Mode	–I6, –A6, –C7, –I7		–A7		–C8		Unit
			Min	Max	Min	Max	Min	Max	
		×2	5	360	5	320	5	320	MHz
		×1	5	360	5	320	5	320	MHz
HSIODR	Data rate (high-speed I/O performance pin)	×10	100	700	100	640	100	640	Mbps
		×8	80	720	80	640	80	640	Mbps
		×7	70	700	70	640	70	640	Mbps
		×4	40	720	40	640	40	640	Mbps
		×2	20	720	20	640	20	640	Mbps
		×1	10	360	10	320	10	320	Mbps
f_{HSCLK}	Input clock frequency (low-speed I/O performance pin)	×10	5	150	5	150	5	150	MHz
		×8	5	150	5	150	5	150	MHz
		×7	5	150	5	150	5	150	MHz
		×4	5	150	5	150	5	150	MHz
		×2	5	150	5	150	5	150	MHz
		×1	5	300	5	300	5	300	MHz
HSIODR	Data rate (low-speed I/O performance pin)	×10	100	300	100	300	100	300	Mbps
		×8	80	300	80	300	80	300	Mbps
		×7	70	300	70	300	70	300	Mbps
		×4	40	300	40	300	40	300	Mbps
		×2	20	300	20	300	20	300	Mbps
		×1	10	300	10	300	10	300	Mbps
SW	Sampling window (high-speed I/O performance pin)	—	—	510	—	510	—	510	ps

continued...

Symbol	Parameter	Mode	–I6, –A6, –C7, –I7		–A7		–C8		Unit
			Min	Max	Min	Max	Min	Max	
	Sampling window (low-speed I/O performance pin)	—	—	910	—	910	—	910	ps
$t_{x\ Jitter}$[72]	Input jitter	—	—	500	—	500	—	500	ps
t_{LOCK}	Time required for the PLL to lock, after CONF_DONE signal goes high, indicating the completion of device configuration	—	—	1	—	1	—	1	ms

Memory Standards Supported by the Soft Memory Controller

Table 47. Memory Standards Supported by the Soft Memory Controller for Intel MAX 10 Devices

Contact your local sales representatives for access to the -I6 or -A6 speed grade devices in the Intel Quartus Prime software.

External Memory Interface Standard	Rate Support	Speed Grade	Voltage (V)	Max Frequency (MHz)
DDR3 SDRAM	Half	–I6	1.5	303
DDR3L SDRAM	Half	–I6	1.35	303
DDR2 SDRAM	Half	–I6	1.8	200
		–I7 and –C7		167
LPDDR2[73]	Half	–I6	1.2	200[74]

Related Information

External Memory Interface Spec Estimator
Provides the specific details of the memory standards supported.

(72) TX jitter is the jitter induced from core noise and I/O switching noise.

(73) Intel MAX 10 devices support only single-die LPDDR2.

(74) To achieve the specified performance, constrain the memory device I/O and core power supply variation to within ±3%. By default, the frequency is 167 MHz.

JTAG Timing Parameters

Table 49. JTAG Timing Parameters for Intel MAX 10 Devices

The values are based on C_L = 10 pF of TDO.

The affected Boundary Scan Test (BST) instructions are SAMPLE/PRELOAD, EXTEST, INTEST, and CHECK_STATUS.

Symbol	Parameter	Non-BST and non-CONFIG_IO Operation		BST and CONFIG_IO Operation		Unit
		Minimum	Maximum	Minimum	Maximum	
t_{JCP}	TCK clock period	40	—	50	—	ns
t_{JCH}	TCK clock high time	20	—	25	—	ns
t_{JCL}	TCK clock low time	20	—	25	—	ns
t_{JPSU_TDI}	JTAG port setup time	2	—	2	—	ns
t_{JPSU_TMS}	JTAG port setup time	3	—	3	—	ns
t_{JPH}	JTAG port hold time	10	—	10	—	ns
t_{JPCO}	JTAG port clock to output	—	• 15 (for V_{CCIO} = 3.3, 3.0, and 2.5 V) • 17 (for V_{CCIO} = 1.8 and 1.5 V)	—	• 18 (for V_{CCIO} = 3.3, 3.0, and 2.5 V) • 20 (for V_{CCIO} = 1.8 and 1.5 V)	ns
t_{JPZX}	JTAG port high impedance to valid output	—	• 15 (for V_{CCIO} = 3.3, 3.0, and 2.5 V) • 17 (for V_{CCIO} = 1.8 and 1.5 V)	—	• 15 (for V_{CCIO} = 3.3, 3.0, and 2.5 V) • 17 (for V_{CCIO} = 1.8 and 1.5 V)	ns
t_{JPXZ}	JTAG port valid output to high impedance	—	• 15 (for V_{CCIO} = 3.3, 3.0, and 2.5 V) • 17 (for V_{CCIO} = 1.8 and 1.5 V)	—	• 15 (for V_{CCIO} = 3.3, 3.0, and 2.5 V) • 17 (for V_{CCIO} = 1.8 and 1.5 V)	ns

Remote System Upgrade Circuitry Timing Specifications

Table 50. Remote System Upgrade Circuitry Timing Specifications for Intel MAX 10 Devices

Parameter	Device	Minimum	Maximum	Unit
$t_{MAX\_RU\_CLK}$	All	—	40	MHz
$t_{RU\_nCONFIG}$	10M02, 10M04, 10M08, 10M16, 10M25	250	—	ns
	10M40, 10M50	350	—	ns
$t_{RU\_nRSTIMER}$	10M02, 10M04, 10M08, 10M16, 10M25	300	—	ns
	10M40, 10M50	500	—	ns

User Watchdog Internal Circuitry Timing Specifications

Table 51. User Watchdog Timer Specifications for Intel MAX 10 Devices

The specifications are subject to PVT changes.

Parameter	Device	Minimum	Typical	Maximum	Unit
User watchdog frequency	10M02, 10M04, 10M08, 10M16, 10M25	3.4	5.1	7.3	MHz
	10M40, 10M50	2.2	3.3	4.8	MHz

Uncompressed Raw Binary File (.rbf) Sizes

Table 52. Uncompressed .rbf Sizes for Intel MAX 10 Devices

Device	CFM Data Size (bits)	
	Without Memory Initialization	With Memory Initialization
10M02	554,000	—
10M04	1,540,000	1,880,000
10M08	1,540,000	1,880,000
10M16	2,800,000	3,430,000

continued...

Table 54. Internal Configuration Time for Intel MAX 10 Devices (Compressed .rbf)

Compression ratio depends on design complexity. The minimum value is based on the best case (25% of original `.rbf` sizes) and the maximum value is based on the typical case (70% of original `.rbf` sizes).

Device	Internal Configuration Time (ms)			
	Unencrypted/Encrypted			
	Without Memory Initialization		With Memory Initialization	
	Min	Max	Min	Max
10M02	0.3	5.2	—	—
10M04	0.6	10.7	1.0	13.9
10M08	0.6	10.7	1.0	13.9
10M16	1.1	17.9	1.4	22.3
10M25	1.1	26.9	1.4	32.2
10M40	2.6	66.1	3.2	82.2
10M50	2.6	66.1	3.2	82.2

Internal Configuration Timing Parameter

Table 55. Internal Configuration Timing Parameter for Intel MAX 10 Devices

Symbol	Parameter	Device	Minimum	Maximum	Unit
t_{CD2UM}	`CONF_DONE` high to user mode	10M02, 10M04, 10M08, 10M16, 10M25	182.8	385.5	µs
		10M40, 10M50	275.3	605.7	µs

I/O Timing

The data is typically used prior to designing the FPGA to get an estimate of the timing budget as part of the link timing analysis.

The Intel Quartus Prime Timing Analyzer provides a more accurate and precise I/O timing data based on the specific device and design after you complete place-and-route.

Table 56. I/O Timing for Intel MAX 10 Devices

These I/O timing parameters are for the 3.3-V LVTTL I/O standard with the maximum drive strength and fast slew rate for 10M08DAF484 device.

Symbol	Parameter	–C7, –I7	–C8	Unit
T_{su}	Global clock setup time	–0.750	–0.808	ns
T_h	Global clock hold time	1.180	1.215	ns
T_{co}	Global clock to output delay	5.131	5.575	ns
T_{pd}	Best case pin-to-pin propagation delay through one LUT	4.907	5.467	ns

Programmable IOE Delay

Programmable IOE Delay On Row Pins

Table 57. IOE Programmable Delay on Row Pins for Intel MAX 10 Devices

The incremental values for the settings are generally linear. For exact values of each setting, refer to the **Assignment Name** column in the latest version of the Intel Quartus Prime software.

The minimum and maximum offset timing numbers are in reference to setting '0' as available in the Intel Quartus Prime software.

Parameter	Paths Affected	Number of Settings	Minimum Offset	Maximum Offset							Unit
				Fast Corner		Slow Corner					
				–I7	–C8	–A6	–C7	–C8	–I7	–A7	
Input delay from pin to internal cells	Pad to I/O dataout to core	7	0	0.815	0.873	1.831	1.811	1.874	1.871	1.922	ns
Input delay from pin to input register	Pad to I/O input register	8	0	0.924	0.992	2.081	2.055	2.125	2.127	2.185	ns
Delay from output register to output pin	I/O output register to pad	2	0	0.479	0.514	1.069	1.070	1.117	1.105	1.134	ns

Programmable IOE Delay for Column Pins

Table 58. IOE Programmable Delay on Column Pins for Intel MAX 10 Devices

The incremental values for the settings are generally linear. For exact values of each setting, refer to the **Assignment Name** column in the latest version of the Intel Quartus Prime software.

The minimum and maximum offset timing numbers are in reference to setting '0' as available in the Intel Quartus Prime software.

Parameter	Paths Affected	Number of Settings	Minimum Offset	Maximum Offset							Unit
				Fast Corner		Slow Corner					
				–I7	–C8	–A6	–C7	–C8	–I7	–A7	
Input delay from pin to internal cells	Pad to I/O dataout to core	7	0	0.81	0.868	1.823	1.802	1.864	1.862	1.912	ns
Input delay from pin to input register	Pad to I/O input register	8	0	0.914	0.981	2.06	2.032	2.101	2.102	2.161	ns
Delay from output register to output pin	I/O output register to pad	2	0	0.435	0.466	0.971	0.97	1.013	1.001	1.028	ns

Date	Version	Changes
January 2016	2016.01.22	• Added description about automotive temperature devices in the Programming/Erasure Specifications table. • Changed the pin capacitance to maximum values. • Updated maximum TCCS specifications from 410 ps to 300 ps in the following tables: — True PPDS and Emulated PPDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices — True RSDS and Emulated RSDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices — Emulated RSDS_E_1R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices — True Mini-LVDS and Emulated Mini-LVDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices — True LVDS Transmitter Timing Specifications for Intel MAX 10 Single Supply Devices — True LVDS Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices — Emulated LVDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Single Supply Devices — Emulated LVDS_E_3R, SLVS, and Sub-LVDS Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices • Added new table: True RSDS and Emulated RSDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Single Supply Devices. • Updated maximum f_{HSCLK} and HSIODR specifications for –A6, –C7, and –I7 speed grades in True LVDS Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices table. • Updated SW specifications in the following tables: — LVDS Receiver Timing Specifications for Intel MAX 10 Single Supply Devices — LVDS, TMDS, HiSpi, SLVS, and Sub-LVDS Receiver Timing Specifications for Intel MAX 10 Dual Supply Devices • Updated maximum f_{HSCLK} and HSIODR (high-speed I/O performance pin) specifications for –I6, –A6, –C7, –I7 speed grades in LVDS, TMDS, HiSpi, SLVS, and Sub-LVDS Receiver Timing Specifications for Intel MAX 10 Dual Supply Devices table. • Removed Internal Configuration Time information in the Uncompressed .rbf Sizes for Intel MAX 10 Devices table. • Added Internal Configuration Time tables for uncompressed `.rbf` files and compressed `.rbf` files. • Removed Preliminary tags for all tables.
November 2015	2015.11.02	• Added description to *Maximum Allowed Overshoot During Transitions over a 11.4-Year Time Frame* topic. • Added ADC_VREF Pin Leakage Current for Intel MAX 10 Devices table. • Updated the condition for "Bus-hold high, sustaining current" parameter from "$V_{IN} < V_{IL}$ (minimum)" to "$V_{IN} < V_{IH}$ (minimum)" in Bus Hold Parameters table.

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Date	Version	Changes
May 2015	2015.05.04	• Updated a note to V_{CCIO} for both single supply and dual supply power supplies recommended operating conditions tables. Note updated: V_{CCIO} for all I/O banks must be powered up during user mode because V_{CCIO} I/O banks are used for the ADC and I/O functionalities. • Updated Example for OCT Resistance Calculation after Calibration at Device Power-Up. • Removed a note to BLVDS in Differential I/O Standards Specifications for Intel MAX 10 Devices table. BLVDS is now supported in Intel MAX 10 single supply devices. Note removed: BLVDS TX is not supported in single supply devices. • Updated ADC Performance Specifications for both single supply and dual supply devices. — Changed the symbol for Operating junction temperature range parameter from T_A to T_J. — Edited sampling rate maximum value from 1000 kSPS to 1 MSPS. — Added a note to analog input voltage parameter. — Removed input frequency, f_{IN} specification. — Updated the condition for DNL specification: External V_{REF}, no missing code. Added DNL specification for condition: Internal V_{REF}, no missing code. — Added notes to AC accuracy specifications that the value with prescalar enabled is 6dB less than the specification. — Added a note to On-Chip Temperature Sensor (absolute accuracy) parameter about the averaging calculation. • Updated ADC Performance Specifications for Intel MAX 10 Single Supply Devices table. — Added condition for On-Chip Temperature Sensor (absolute accuracy) parameter: with 64 samples averaging. • Updated ADC Performance Specifications for Intel MAX 10 Dual Supply Devices table. — Updated Digital Supply Voltage minimum value from 1.14 V to 1.15 V and maximum value from 1.26 V to 1.25 V. • Updated f_{HSCLK} and HSIODR specifications for –A7 speed grade in the following tables: — True PPDS and Emulated PPDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices — True RSDS and Emulated RSDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices — True Mini-LVDS and Emulated Mini-LVDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices — True LVDS Transmitter Timing Specifications for Intel MAX 10 Single Supply Devices — True LVDS Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices — Emulated LVDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Single Supply Devices — Emulated LVDS_E_3R, SLVS, and Sub-LVDS Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices — LVDS Receiver Timing Specifications for Intel MAX 10 Single Supply Devices — LVDS, TMDS, HiSpi, SLVS, and Sub-LVDS Receiver Timing Specifications for Intel MAX 10 Dual Supply Devices

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Date	Version	Changes
		• Updated TCCS specifications in the following tables: — True PPDS and Emulated PPDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices — True RSDS and Emulated RSDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices — Emulated RSDS_E_1R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices — True Mini-LVDS and Emulated Mini-LVDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices — True LVDS Transmitter Timing Specifications for Intel MAX 10 Single Supply Devices — True LVDS Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices — Emulated LVDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Single Supply Devices — Emulated LVDS_E_3R, SLVS, and Sub-LVDS Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices • Updated $t_{x\ Jitter}$ specifications in the following tables: — True PPDS and Emulated PPDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices — True RSDS and Emulated RSDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices — Emulated RSDS_E_1R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices — True Mini-LVDS and Emulated Mini-LVDS_E_3R Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices — True LVDS Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices — Emulated LVDS_E_3R, SLVS, and Sub-LVDS Transmitter Timing Specifications for Intel MAX 10 Dual Supply Devices • Updated SW specifications in LVDS Receiver Timing Specifications for Intel MAX 10 Single Supply Devices table. • Added a note to $t_{x\ Jitter}$ for all LVDS tables. Note: TX jitter is the jitter induced from core noise and I/O switching noise. • Updated the description for t_{LOCK} for all LVDS tables: Time required for the PLL to lock, after CONF_DONE signal goes high, indicating the completion of device configuration. • Updated Memory Output Clock Jitter Specifications section. — Updated maximum external memory interfaces frequency from 300 MHz to 303 MHz. — Updated PLL output routing from global clock network to PHY clock network. • Added I/O Timing for Intel MAX 10 Devices table. • Added V_{HYS} in the Glossary table.
January 2015	2015.01.23	• Removed a note to V_{CCA} in Power Supplies Recommended Operating Conditions for Intel MAX 10 Dual Supply Devices table. This note is not valid: All V_{CCA} pins must be connected together for EQFP package. • Corrected the maximum value for $t_{OUTJITTER\_CCJ\_IO}$ ($F_{OUT} \geq 100$ MHz) from 60 ps to 650 ps in PLL Specifications for Intel MAX 10 Devices table.
December 2014	2014.12.15	• Restructured Programming/Erasure Specifications for Intel MAX 10 Devices table to add temperature specifications that affect the data retention duration. • Added statements in the I/O Pin Leakage Current section: Input channel leakage of ADC I/O pins due to hot socket is up to maximum of 1.8 mA. The input channel leakage occurs when the ADC IP core is enabled or disabled. This is applicable to all Intel MAX 10 devices with ADC IP core, which are 10M04, 10M08, 10M16, 10M25, 10M40, and 10M50 devices. The ADC I/O pins are in Bank 1A. • Added a statement in the I/O Standards Specifications section: You must perform timing closure analysis to determine the maximum achievable frequency for general purpose I/O standards.

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